

<b>Notice of References Cited</b>	Application/Control No. 10/616,097		Applicant(s)/Patent Under Reexamination SUN ET AL.	
	Examiner EDNA WONG		Art Unit 1795	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2005/0020068	01-2005	Wang et al.	438/687
*	B	US-6,432,821	08-2002	Dubin et al.	438/678
*	C	US-6,709,563	03-2004	Nagai et al.	205/123
*	D	US-6,242,349	06-2001	Nogami et al.	438/687
*	E	US-2004/0108217	06-2004	Dubin, Valery M.	205/291
*	F	US-7,192,494	03-2007	Chen et al.	148/518
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 2002076000 A	03-2002	Japan	TAGUCHI et al.	H01L 21/3205
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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